

ICR HV500-75 set

Near-Field Microprobe 200 kHz - 1 GHz



Short description

The near-field microprobe is designed for a high-resolution measurement of magnetic near fields. With the ICR H probe the following measurements can be performed:

- Surface Scan via IC according to IEC 61967-3
- Volumenscan via IC
- Pin Scan

The measuring coil at the ICR RF probe head is vertically aligned to the measurement surface. A preamplifier is integrated into the probe housing and powered by the Bias-Tee. The ICR near-field probes undergo a quality check before they are delivered. Different reference setup measurements are performed and resulting correction lines are generated. Three different correction lines are determined – a standardized correction line, an H-field correction line, and a current correction line.

Attention: Due to its construction, the ICR probe is sensitive to shock and comes with a protective cap for transport and handling.

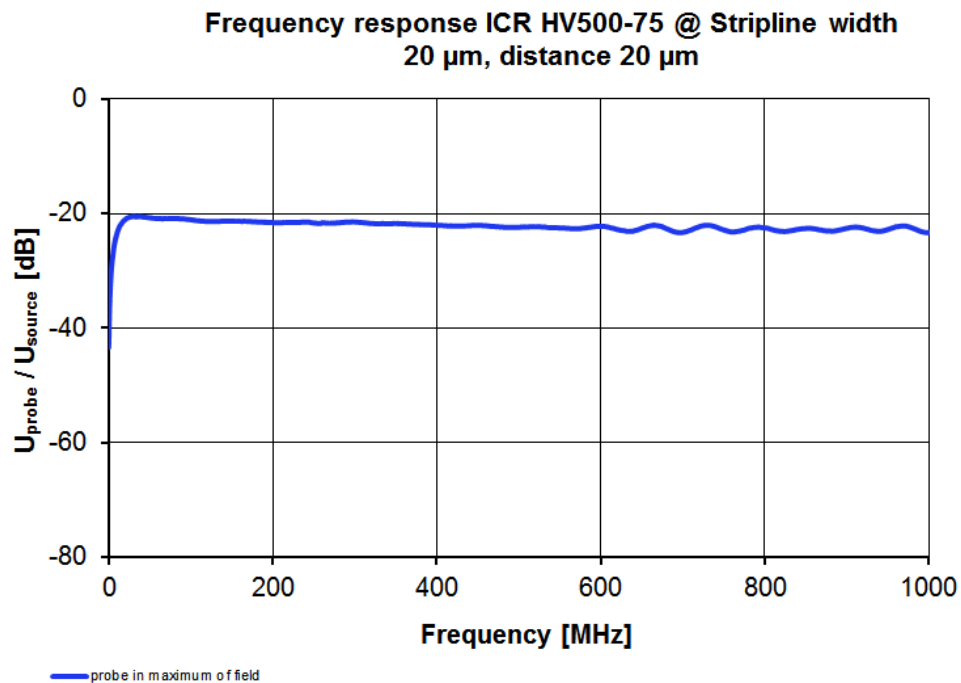
Scope of delivery

- 1x ICR HV500-75, Near-Field Microprobe 200 kHz to 1 GHz
- 1x BT 706, Bias Tee for Langer probes
- 1x SMA-SMA RA, Cable SMA-SMA, right angle
- 1x ICR-C, ICR Certificate
- 1x ICR Corr, Correction Curves ICR / USB
- 1x NT FRI EU, Power Supply Unit
- 1x ICR case1, System Case

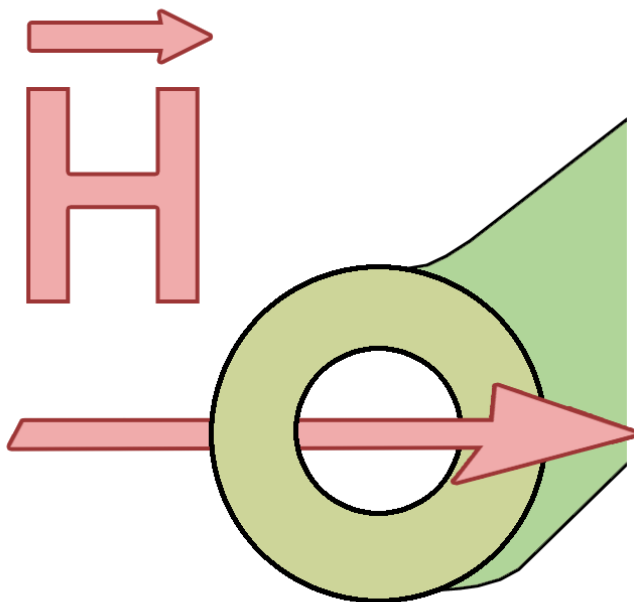
Technical parameters

Frequency range	200 kHz ... 1 GHz
Resolution	300 µm
Internal diameter	500 µm

Frequency response

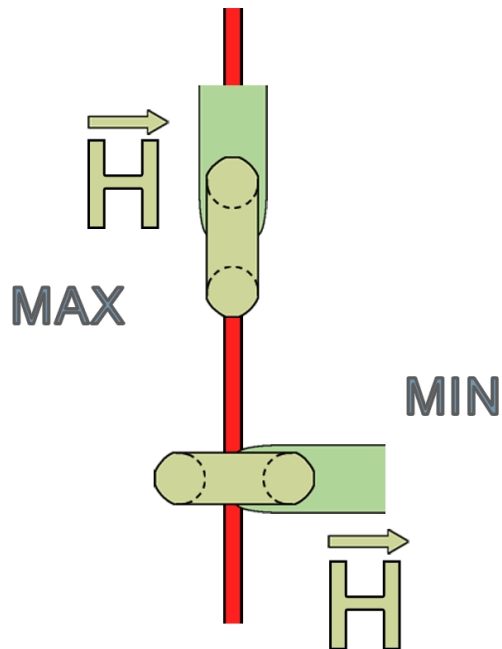


Measuring principles



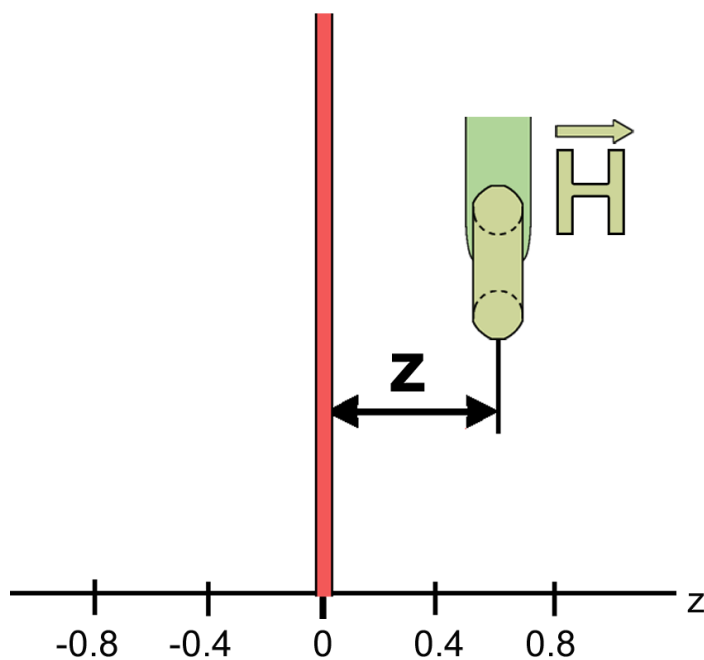
Design, view 1

Stripline

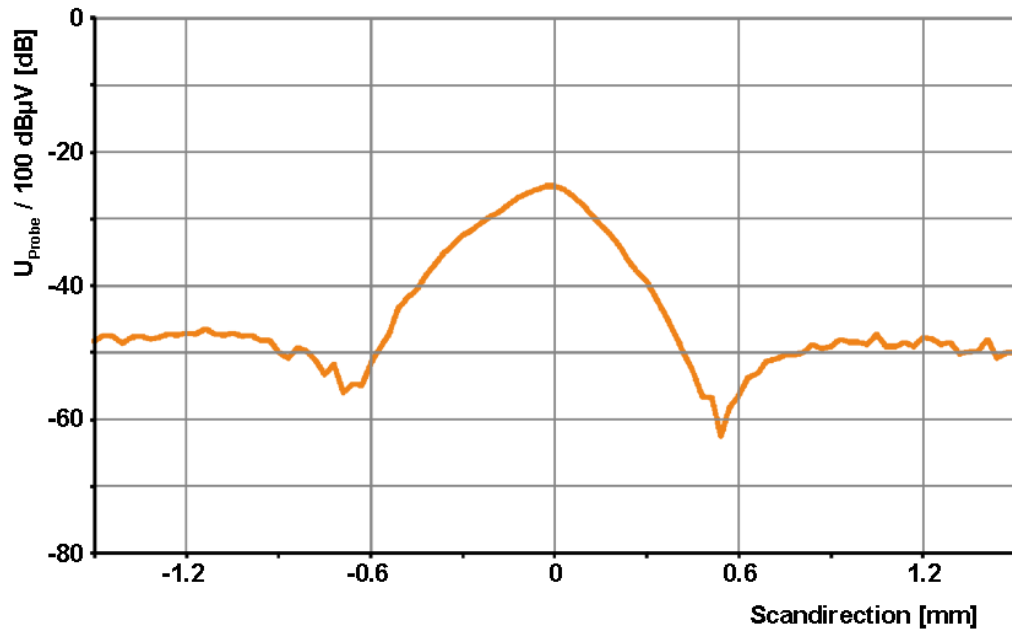


Design, view 2

Stripline



Transverse profile



ICR HV500-75

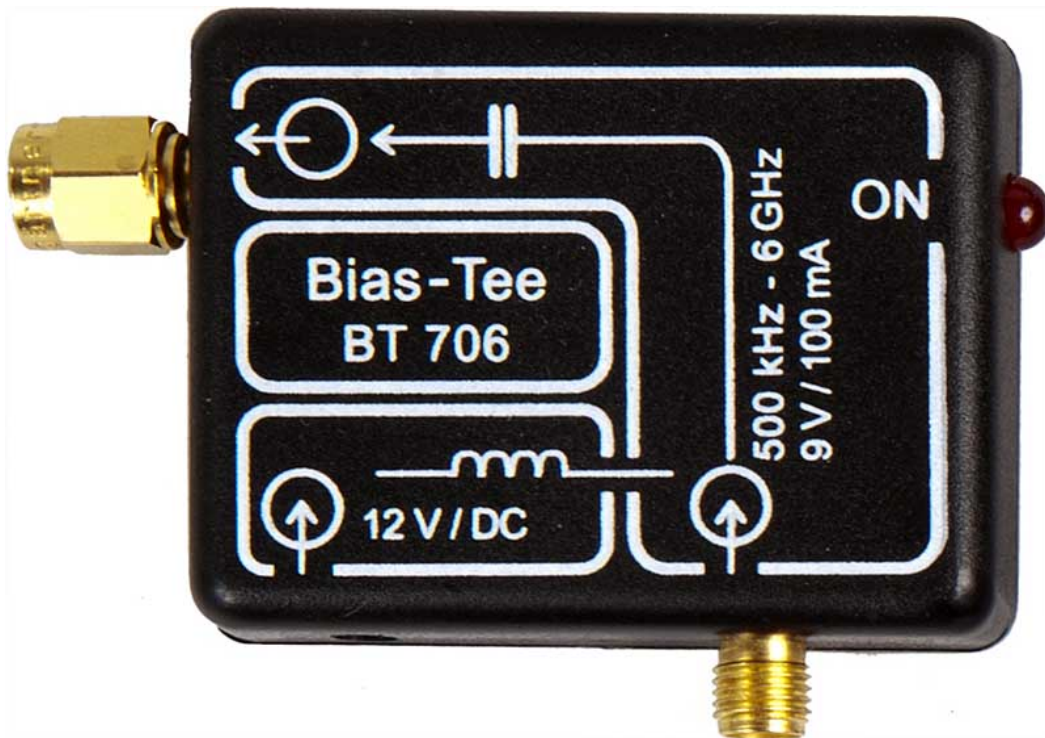


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LANGER
EMV-Technik

BT 706 bias tee



Scope of delivery

